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SN74GTL1655 16-BIT LVTTL-TO-GTL/GTL+ UNIVERSAL BUS TRANSCEIVER WITH LIVE INSERTION

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FEATURES

- Member of the Texas Instruments Widebus™ Family
- UBT[™] Transceiver Combines D-Type Latches and D-Type Flip-Flops for Operation in Transparent, Latched, or Clocked Modes
- OEC[™] Circuitry Improves Signal Integrity and Reduces Electromagnetic Interference
- Translates Between GTL/GTL+ Signal Level and LVTTL Logic Levels
- High-Drive (100 mA), Low-Output-Impedance (12 Ω) Bus Transceiver (B Port)
- Edge-Rate-Control Input Configures the B-Port Output Rise and Fall Times
- I_{off}, Power-Up 3-State, and BIAS V_{CC} Support Live Insertion
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors on A Port
- Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise

DESCRIPTION/ORDERING INFORMATION

The SN74GTL1655 is a high-drive (100 mA), **UBT**TM low-output-impedance (12Ω) 16-bit transceiver that provides LVTTL-to-GTL/GTL+ and GTL/GTL+-to-LVTTL signal-level translation. This device is partitioned as two 8-bit transceivers and combines D-type flip-flops and D-type latches to allow for transparent, latched, and clocked modes of data transfer similar to the '16501 function. This device provides an interface between cards operating at LVTTL logic levels and a backplane operating at GTL/GTL+ signal levels. Higher-speed operation is a direct result of the reduced output swing (<1 V), reduced input threshold levels, and OEC™ circuitry. drive is suitable for high driving double-terminated low-impedance backplanes using incident-wave switching.

DGG PACKAGE (TOP VIEW)

1 OEAB	1	\bigcup_{64}	CLK
	2		1LEAB
	3	62	
	4	61	V _{ERC}
GND	5	60	GND
1A2		59] 1B1
1A3	7	58] 1B2
GND	8	57] GND
1A4	9	56] 1B3
GND	10	55] 1B4
1A5	11	54] 1B5
GND	12	53] GND
1A6	13	52] 1B6
1A7	14	51] 1B7
V _{CC}	15	50] v _{cc}
1A8	16] 1B8
2A1	17	48] 2B1
GND		47] GND
2A2		46] 2B2
2A3	20] 2B3
GND			GND
2A4	22] 2B4
	23	42] 2B5
GND	24	41] V _{REF}
2A6	25] 2B6
GND	26	39] GND
	27		2B7
V _{CC}	28	37] 2B8
2A8	_	36	BIAS V _{CC}
GND		35	2LEAB
2 <mark>OEAB</mark>	31	34	2LEBA
2 <mark>OEBA</mark>	32	33] OE
			•

The user has the flexibility of using this device at either GTL ($V_{TT} = 1.2 \text{ V}$ and $V_{REF} = 0.8 \text{ V}$) or the preferred higher noise margin GTL+ ($V_{TT} = 1.5 \text{ V}$ and $V_{REF} = 1 \text{ V}$) signal levels. GTL+ is the Texas Instruments derivative of the Gunning Transceiver Logic (GTL) JEDEC standard JESD 8-3. The B port normally operates at GTL or GTL+ signal levels, while the A-port and control inputs are compatible with LVTTL logic levels, but are not 5-V tolerant. V_{REF} is the reference input voltage for the B port.



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DESCRIPTION/ORDERING INFORMATION (CONTINUED)

This device is partitioned uniquely as two 8-bit transceivers with individual latch timing and output signals, but with a common clock and output enable inputs for both transceiver words.

Data flow for each word is determined by the respective latch enables (LEAB and LEBA), output enables (OEAB and OEBA), and clock (CLK). The output enables (1OEAB, 1OEBA, 2OEAB, and 2OEBA) control byte 1 and byte 2 data for the A-to-B and B-to-A directions, respectively.

For A-to-B data flow, the devices operate in the transparent mode when LEAB is high. When LEAB transitions low, the A data is latched independent of CLK high or low. If LEAB is low, the A data is registered on the CLK low-to-high transition. When \overline{OEAB} is low, the outputs are active. With \overline{OEAB} high, the outputs are in the high-impedance state.

Data flow for the B-to-A direction is identical, but uses $\overline{\text{OEBA}}$, LEBA, and CLK. Note that CLK is common to both directions and both 8-bit words. $\overline{\text{OE}}$ also is common and is used to disable all I/O ports simultaneously.

The SN74GTL1655 has adjustable edge-rate control (V_{ERC}). Changing V_{ERC} input voltage between GND and V_{CC} adjusts the B-port output rise and fall times. This allows the designer to optimize for various loading conditions.

This device is fully specified for live-insertion applications using $I_{\rm off}$, power-up 3-state, and BIAS $V_{\rm CC}$. The $I_{\rm off}$ circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict. The BIAS $V_{\rm CC}$ circuitry precharges and preconditions the B-port input/output connections, preventing disturbance of active data on the backplane during card insertion or removal, and permits true live-insertion capability.

When V_{CC} is between 0 and 1.5 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry holds unused or undriven LVTTL inputs at a valid logic state. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.

ORDERING INFORMATION

T _A	PACKAGE ⁽¹⁾		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	TSSOP – DGG	Tape and reel	SN74GTL1655DGGR	GTL1655

⁽¹⁾ Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

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FUNCTION TABLES

FUNCTION⁽¹⁾

INPUTS				OUTPUT	MODE
OEAB	LEAB	CLK	Α	В	MODE
Н	Χ	X	X	Z	Isolation
L	Н	X	L	L	Transparent
L	Н	X	Н	Н	Transparent
L	L	\uparrow	L	L	Registered
L	L	\uparrow	Н	Н	Registered
L	L	Н	Χ	B ₀ ⁽²⁾	Previous state
L	L	L	Χ	B ₀ ⁽³⁾	Previous state

- A-to-B data flow is shown. B-to-A flow is similar, but uses OEBA, LEBA, and CLK.
- (2) Output level before the indicated steady-state input conditions were established, provided that CLK was high before LEAB went low
- (3) Output level before the indicated steady-state input conditions were established

OUTPUT ENABLE

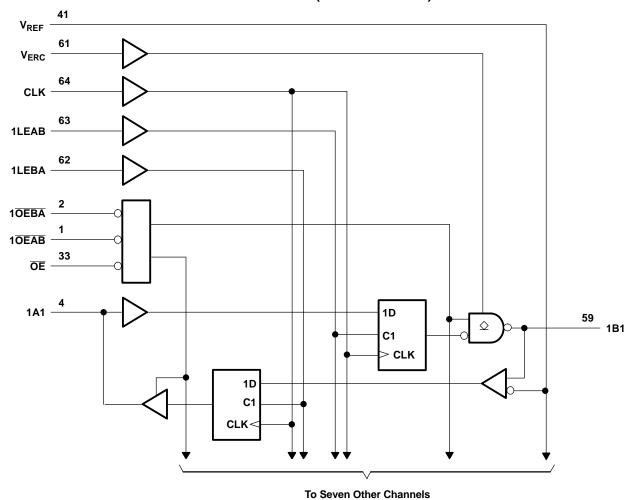
INPUTS			OUT	PUTS
ŌĒ	OEAB	OEBA	A PORT	B PORT
L	L	L	Active	Active
L	L	Н	Z	Active
L	Н	L	Active	Z
L	Н	Н	Z	Z
Н	X	Χ	Z	Z

B-PORT EDGE-RATE CONTROL (VERC)

in	put V _{ERC}	OUTPUT
LOGIC LEVEL	NOMINAL VOLTAGE	B-PORT EDGE RATE
Н	V _{CC}	Slow
L	GND	Fast



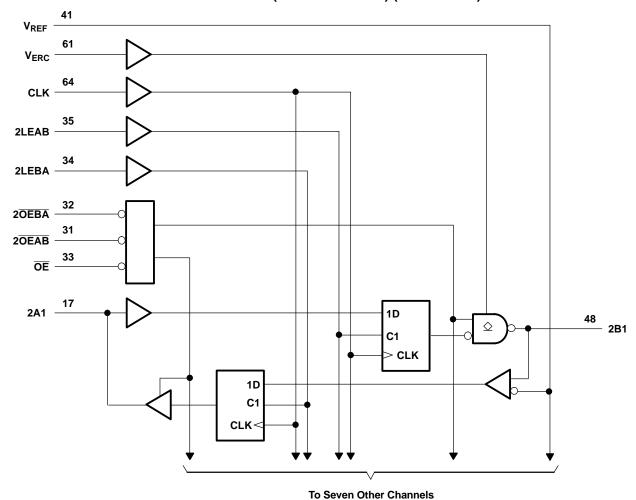
LOGIC DIAGRAM (POSITIVE LOGIC)





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LOGIC DIAGRAM (POSITIVE LOGIC) (CONTINUED)



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Absolute Maximum Ratings⁽¹⁾

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC} BIAS V_{CC}	Supply voltage range			4.6	V
V	Input voltage range ⁽²⁾	A-port and control inputs	-0.5	4.6	V
VI	input voltage range -/	B port, V_{ERC} , and V_{REF}	-0.5	4.6	V
V	Voltage range applied to any output in the high or power-off state (2)	A port	-0.5	4.6	V
Vo	voltage range applied to any output in the high of power-on state (=)	B port	-0.5 4.6	V	
	Current into any autaut in the law state	A port		48	mA
I _O C	Current into any output in the low state	B port		200	IIIA
Io	Current into any A-port output in the high state (3)			48	mA
	Continuous current through each V _{CC} or GND			±100	mA
I_{lK}	Input clamp current	V _I < 0		-50	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
θ_{JA}	Package thermal impedance (4)			55	°C/W
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

The current flows only when the output is in the high state and $V_{\rm O} > V_{\rm CC}$. The package thermal impedance is calculated in accordance with JESD 51-7.

Recommended Operating Conditions (1)(2)(3)(4)

			MIN	NOM	MAX	UNIT
BIAS V _{CC}	Supply voltage		3	3.3	3.6	V
	Tanadaattaa saltaa	GTL	1.14	1.2	1.26	
V_{TT}	Termination voltage	GTL+	1.35	1.5	1.65	V
	Defenses valteres	GTL	0.74	0.8	0.87	V
V_{REF}	Reference voltage	GTL+	0.87	1	1.1	V
	langut valtana	B port	0		V _{TT}	V
V _I	Input voltage	Except B port	0		V _{CC}	V
V _{IH}	High-level input voltage	B port	V _{REF} + 50 mV			
		V _{ERC}	V _{CC} - 0.6	V _{CC}		V
		Except B port and ERC	2			
		B port		١	/ _{REF} – 50 mV	
V_{IL}	Low-level input voltage	V _{ERC}		GND	0.6	V
		Except B port and ERC			3.6 1.26 1.65 0.87 1.1 V _{TT} V _{CC}	
I _{IK}	Input clamp current				-18	mA
I _{OH}	High-level output current	A port			-24	mA
	Lour lovel output output	A port			24	mA
l _{OL}	Low-level output current	B port			100	mA
$\Delta t/\Delta V_{CC}$	Power-up ramp rate		200			μs/V
T _A	Operating free-air temperature		-40		85	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

Normal connection sequence is GND first, BIAS V_{CC} = 3.3 V second, and V_{CC} = 3.3 V, I/O, control inputs, V_{TT} and V_{REF} (any order) last. However, if the B-port I/O precharge is not required, the acceptable connection sequence is GND first and $V_{CC} = 3.3 \text{ V}$, BIAS $V_{CC} = 3.3 \text{ V}$, I/O, control inputs, V_{TT} and V_{REF} (any order) last. When V_{CC} is connected, the BIAS V_{CC} circuitry is disabled.

 V_{TT} and R_{TT} can be adjusted to accommodate backplane impedances if the dc recommended I_{OL} ratings are not exceeded. V_{REF} can be adjusted to optimize noise margins, but normally is two-thirds V_{TT} .



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Electrical Characteristics

over recommended operating free-air temperature range, $V_{REF} = 1 \text{ V}$ and $V_{TT} = 1.5 \text{ V}$ (unless otherwise noted)

	PARAMETER	TEST	CONDITIONS	MIN T	(P ⁽¹⁾ MAX	UNIT
V_{IK}		$V_{CC} = 3 V$,	$I_{I} = -18 \text{ mA}$		-1.2	V
		$V_{CC} = 3 \text{ V to } 3.6 \text{ V},$	$I_{OH} = -100 \mu A$	V _{CC} - 0.2		
V_{OH}	A port	V 0.V	$I_{OH} = -12 \text{ mA}$	2.4		V
		$V_{CC} = 3 V$	$I_{OH} = -24 \text{ mA}$	2.2		
		$V_{CC} = 3 \text{ V to } 3.6 \text{ V},$	I _{OL} = 100 μA		0.2	
	A port	V 0.V	I _{OL} = 12 mA		0.4	
.,		$V_{CC} = 3 V$	I _{OL} = 24 mA		0.55	
V_{OL}			I _{OL} = 40 mA		0.2	V
	B port	V _{CC} = 3 V	I _{OL} = 80 mA		0.4	
			I _{OL} = 100 mA		0.5	
	Control inputs	V 00V	$V_I = V_{CC}$ or GND		±10	^
I _I B port	B port	V _{CC} = 3.6 V	$V_I = V_{TT}$ or GND		±10	μΑ
I _{off}		$V_{CC} = 0$,	V_{1} or $V_{0} = 0$ to 3.6 V		±100	μΑ
	A port	v _{CC} = 3 V	V _I = 0.8 V	75		
I _{I(hold)}			V _I = 2 V	-75		μΑ
, ,		$V_{CC} = 3.6 V^{(2)},$	$V_I = 0$ to V_{CC}		±500	
l _{ozh}	B port	V _{CC} = 3.6 V,	V _O = 1.5 V		10	μΑ
I _{OZL}	B port	V _{CC} = 3.6 V,	V _O = 0.4 V		-10	μΑ
I _{OZ} (3)	A port	V _{CC} = 3.6 V,	$V_O = V_{CC}$ or GND		±10	μΑ
I _{OZPU}	A port	$V_{CC} = 0 \text{ to } 3.6 \text{ V}, V_{O} = 0.5$	V to 3 V, $\overline{OE} = low$		±50	μΑ
I _{OZPD}	A port	$V_{CC} = 3.6 \text{ V to } 0, V_{O} = 0.5$	V to 3 V, $\overline{OE} = low$		±50	μΑ
			Outputs high		80	
I_{CC}	A or B port	$V_{CC} = 3.6 \text{ V}, I_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low		80	mA
		1 = AGG OL GIAD	Outputs disabled		80	
ΔI _{CC} ⁽⁴⁾	Except B port	$V_{CC} = 3.6 \text{ V}$, A-port or cont One input at $V_{CC} - 0.6 \text{ V}$	rol inputs at V _{CC} or GND,		1	mA
C _i	Control inputs	$V_I = V_{CC}$ or 0			3 5	pF
^	A port	\/ \/ or 0			5 6	~F
C_{io}	B port	$V_O = V_{CC}$ or 0			6 8	pF

- (1) All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$. (2) This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to
- (3) For I/O ports, the parameter I_{OZ} includes the input leakage current.
 (4) This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

Live-Insertion Specifications

over recommended operating free-air temperature range

PA	RAMETER		TEST CONDITIONS				UNIT
I (DIA	C \/ \	$V_{CC} = 0$ to 3 V	\/ (P nort) = 0 to 1 2 \/	V (BIAS V) = 2 V to 2 6 V		5	mA
I _{CC} (BIA	S V _{CC})	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V_0 (B port) = 0 to 1.2 V,	V_I (BIAS V_{CC}) = 3 V to 3.6 V		10	μΑ
Vo	B port	$V_{CC} = 0$,	V_{I} (BIAS V_{CC}) = 3.3 V		1	1.2	V
		$V_{CC} = 0$,	V_O (B port) = 0.4 V,	V_I (BIAS V_{CC}) = 3 V to 3.6 V	-1		
Io	B port	$V_{CC} = 0 \text{ to } 3.6 \text{ V},$	OE = 3.3 V			100	μΑ
		$V_{CC} = 0 \text{ to } 1.5 \text{ V},$	OE = 0 to 3.3 V			100	

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Timing Requirements

over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.2 V, V_{REF} = 0.8 V, and V_{ERC} = V_{CC} or GND for GTL (unless otherwise noted)

				MIN	MAX	UNIT
f _{clock}	Clock frequency				160	MHz
	Pulse duration	LE high		3		
t _w Pulse duration	CLK high or low		3		ns	
		Data before CLK↑	•	2.7		
t _{su}	Setup time	Data hafara I 5	CLK high	2.8		ns
		Data before LE↓	CLK low	2.6		
	Hald time	Data after CLK↑		0.4		
t _h	поіа ште	Hold time Data after LE↓	CLK high or low	0.9		ns

A-to-B Switching Characteristics

over recommended ranges of supply voltage and operating free-air temperature,

 $V_{TT} = 1.2 \text{ V}$, $V_{REF} = 0.8 \text{ V}$, and $V_{ERC} = V_{CC}$ or GND for GTL (see Figure 1)

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
	f _{max}			160			MHz
	t _{PLH}	А	В	3.1		5.2	20
	t _{PHL}	$V_{ERC} = V_{CC}$	В	2.6		6.2	ns
	t _{PLH}	CLK	В	3.4		5.5	ns
	t _{PHL}	$V_{ERC} = V_{CC}$	Б	2.4		5.8	115
	t _{PLH}	LEAB	В	3.5		5.8	ns
	t _{PHL}	$V_{ERC} = V_{CC}$	В	2.6		6.4	115
	t _{en}	OEAB or OE	В	3.3		5.4	
	t_{dis}	$V_{ERC} = V_{CC}$	Ь	2.7		5.9	ns
	t _{PLH}	А	В	2.3		4.3	ns
	t _{PHL}	$V_{ERC} = GND$	Б	1.9		4.3	115
	t _{PLH}	CLK V _{ERC} = GND	В	2.7		4.8	ns
	t _{PHL}			1.8		4.3	115
	t _{PLH}	LEAB	В	2.8		4.9	20
	t _{PHL}	$V_{ERC} = GND$	В	2		4.8	ns
	t _{en}	OEAB or OE	В	2.5		4.5	ne
	t_{dis}	$V_{ERC} = GND$	Ь	2		4.2	ns
	$V_{ERC} = GND$	Transition time P.	outputs (0.6 V to 1 V)		0.6		ns
t _r	$V_{ERC} = V_{CC}$	Transition time, b c	outputs (0.6 V to 1 V)	2.8 4.9 2 4.8 2.5 4.5 2 4.2 0.6 1.2 1.1		115	
	V _{ERC} = GND	Transition time P.	outputs (1 V to 0.6 V)		1.1		20
t _f	$V_{ERC} = V_{CC}$	Transition time, b c	outputs (1 v to 0.6 v)		1.7		ns
	t _{sk(o)} ⁽¹⁾	Skew between driver switching in the	s in the same package e same direction			1	ns
	t _{sk(o)} (2)		veen drivers on in the same package			1	ns

⁽¹⁾ Skew values are applicable for through mode only.

⁽²⁾ Skew values are applicable for CLK mode only, with all outputs switching simultaneously.



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B-to-A Switching Characteristics

over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.2 V and V_{REF} = 0.8 V for GTL (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
f _{max}			160		MHz
t _{PLH}	В	A	1.8	4.7	ns
t _{PHL}	В	A	2.3	4.6	115
t _{PLH}	CLK	CLK A	1.6	4	
t _{PHL}	CLK		1.5	3.4	ns
t _{PLH}	LEBA	^	1.7	4	20
t _{PHL}	LEBA	A	1.4	3.5	ns
t _{en}	OEBA or OE	^	1.2	4.2	20
t _{dis}	OEBA OI OE	A	1.2	6.1	ns
t _{sk(o)} ⁽¹⁾		s in the same package same direction		1	ns
t _{sk(o)} (2)		een drivers on in the same package		1	ns

⁽¹⁾ Skew values are applicable for through mode only.(2) Skew values are applicable for CLK mode only, with all outputs switching simultaneously.

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Timing Requirements

over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.5 V, V_{REF} = 1 V, and V_{ERC} = V_{CC} or GND for GTL+ (unless otherwise noted)

				MIN	MAX	UNIT
f _{clock}	Clock frequency				160	MHz
	Dulgo duration	LE high		3		
ι _w	Pulse duration		3		ns	
		Data before CLK↑		2.7		
t _{su}	t _{su} Setup time	5	CLK high	2.8		ns
		Data before LE↓	CLK low	2.6		
t _h	Hald time	Data after CLK↑		0.4		
	Hold time	Data after LE↓	CLK high or low	0.9		ns

A-to-B Switching Characteristics

over recommended ranges of supply voltage and operating free-air temperature,

 V_{TT} = 1.5 V, V_{REF} = 1 V, and V_{ERC} = V_{CC} or GND for GTL+ (see Figure 1)

PAR	AMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT				
	f _{max}			160			MHz				
	t _{PLH}	Α	В	3		5.1	ns				
	t _{PHL}	$V_{ERC} = V_{CC}$	Ь	2.9		6.5	115				
	t _{PLH}	CLK	В	3.4		5.4	ns				
	t _{PHL}	$V_{ERC} = V_{CC}$	Ь	2.7		6.2	115				
	t _{PLH}	LEAB	В	3.5		5.7	ns				
	t _{PHL}	$V_{ERC} = V_{CC}$	Ь	2.8		6.7	115				
	t _{en}	OEAB	В	3.3		5.4	ns				
	t _{dis}	$V_{ERC} = V_{CC}$	Ь	3		6.3	115				
	t _{en}	ŌĒ	В	3		5.5	ns				
	t _{dis}	$V_{ERC} = V_{CC}$	Ь	3.6		5.8	115				
	t _{PLH}	Α	В	2.3		4.3	ns				
	t _{PHL}	$V_{ERC} = GND$	D	2		4.4	113				
	t _{PLH}	CLK	В	2.7		4.8	ns				
	t _{PHL}	$V_{ERC} = GND$	Ь	1.9		4.5	115				
	t _{PLH}	LEAB	В	2.8		4.9	ns				
	t _{PHL}	$V_{ERC} = GND$	D	2.1		4.9	113				
	t _{en}	OEAB	В	2.5		4.5	ns				
	t _{dis}	$V_{ERC} = GND$	Ь	2.1		4.4	115				
	t _{en}	ŌĒ	В	2.5		4.6	ns				
	t _{dis}	$V_{ERC} = GND$	D	2.9	4.9		113				
t _r	$V_{ERC} = GND$	Transition time R ou	Transition time, B outputs (0.6 V to 1.3 V)				Transition time Ricutauts (0.6 \/ to 1.3 \/)				ns
۲r	$V_{ERC} = V_{CC}$	Transition time, b ou					113				
+	$V_{ERC} = GND$	Transition time, B ou		1.6							
t _f	$V_{ERC} = V_{CC}$	Transition time, b ou		2.4		ns					
t,	sk(o) ⁽¹⁾	Skew between drivers switching in the			1	ns					
t,	sk(o) ⁽²⁾		een drivers on in the same package			1	ns				

⁽¹⁾ Skew values are applicable for through mode only.

⁽²⁾ Skew values are applicable for CLK mode only, with all outputs switching simultaneously.



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B-to-A Switching Characteristics

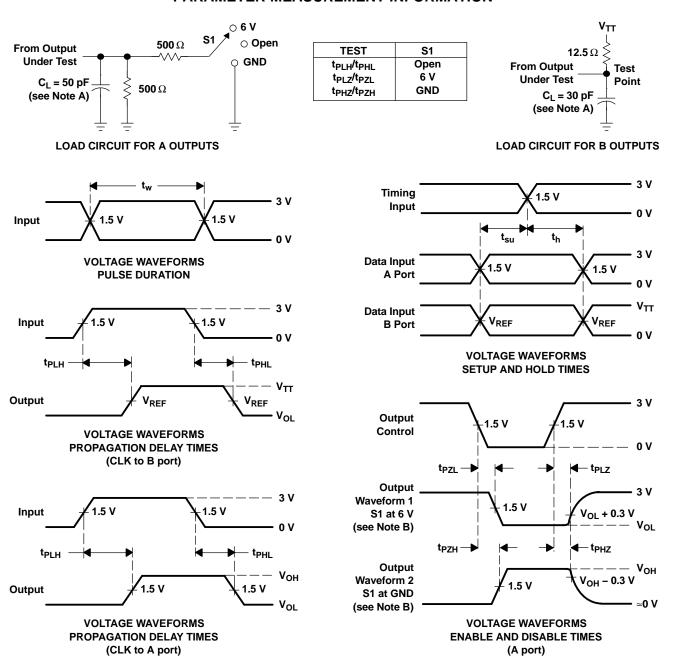
over recommended ranges of supply voltage and operating free-air temperature, V_{TT} = 1.5 V and V_{REF} = 1 V for GTL+ (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
f _{max}			160		MHz
t _{PLH}	В	A	2	4.8	20
t _{PHL}	Ь	A	2.4	4.7	ns
t _{PLH}	CLK	A	1.6	4.4	20
t _{PHL}	CLK	A	1.5	3.4	ns
t _{PLH}	LEBA	A	1.7	4	20
t _{PHL}	LEBA		1.4	3.5	ns
t _{en}	- OEBA	A	1.2	4.2	20
t _{dis}	OEBA	A	1.2	6.1	ns
t _{en}	ŌĒ	A	1.2	4.7	20
t _{dis}	- OE	A	1.2	6.3	ns
t _{sk(o)} ⁽¹⁾		s in the same package asame direction		1	ns
t _{sk(o)} (2)	Skew betw switching in any direction		1	ns	

Skew values are applicable for through mode only. Skew values are applicable for CLK mode only, with all outputs switching simultaneously.



PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{O} = 50 Ω , $t_{f} \leq$ 2.5 ns, $t_{f} \leq$ 2.5 ns.
 - D. The outputs are measured one at a time, with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en}.

Figure 1. Load Circuits and Voltage Waveforms



PACKAGE OPTION ADDENDUM

6-Feb-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
SN74GTL1655DGGR	ACTIVE	TSSOP	DGG	64	2000	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 85	GTL1655	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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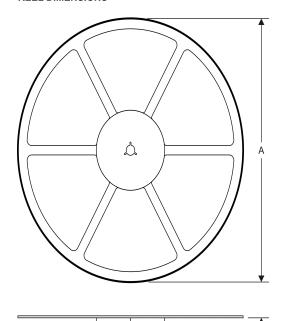
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PACKAGE MATERIALS INFORMATION

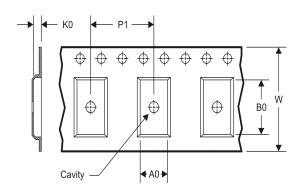
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TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74GTL1655DGGR	TSSOP	DGG	64	2000	330.0	24.4	8.4	17.3	1.7	12.0	24.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
SN74GTL1655DGGR	TSSOP	DGG	64	2000	367.0	367.0	45.0	

DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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